

SEMICONDUCTOR TECHNICAL DATA

2N7000A

N CHANNEL ENHANCEMENT MODE FIELD EFFECT TRANSISTOR

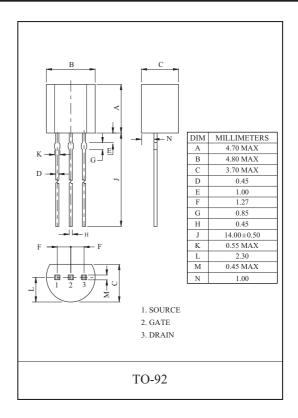
INTERFACE AND SWITCHING APPLICATION.

FEATURES

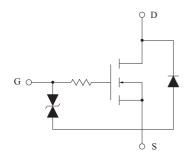
- \cdot High density cell design for low $R_{DS(\mathrm{ON})}.$
- · Voltage controllled small signal switch.
- · Rugged and reliable.
- · High saturation current capablity.

MAXIMUM RATING (Ta=25)

CHARACT	SYMBOL	RATING	UNIT	
Drain-Source Voltag	V _{DSS}	60	V	
Drain-Gate Voltage	(R _{GS} 1MΩ)	V _{DGR} 60		
Gate-Source Voltag	e	V _{GSS} ± 20		
Drain Current	Continuous	I_D	200	mA
	Pulsed	I_{DP}	500	IIIA
Drain Power Dissipa	ation	P _D 400 m		mW
Junction Temperatu	re	T _j	150	
Storage Temperature Range		T_{stg}	-55 150	



EQUIVALENT CIRCUIT



THIS TRANSISTOR IS ELECTROSTATIC SENSITIVE DEVICE. PLEASE HANDLE WITH CAUTION.

ELECTRICAL CHARACTERISTICS (Ta=25)

CHARACTERISTIC	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Drain-Source Breakdown Voltage	BV_{DSS}	$V_{GS}=0V, I_{D}=10 \mu A$	60	-	-	V
Zero Gate Voltage Drain Current	I _{DSS}	V_{DS} =48V, V_{GS} =0V	-	-	1	μA
Gate-Body Leakage, Forward	I_{GSSF}	$V_{GS}=15V, V_{DS}=0V$	-	-	1	μA
Gate-Body Leakage, Reverse	I_{GSSR}	V _{GS} =-15V, V _{DS} =0V	-	-	-1	μA

ELECTRICAL CHARACTERISTICS (Ta=25) ON CHARACTERISTICS (Note 1)

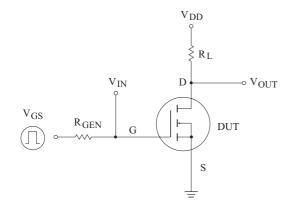
CHARACTERISTIC	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Gate Threshold Voltage	V _{th}	V _{DS} =V _{GS} , I _D =1mA	0.8	2.1	3	V
Drain-Source ON Resistance	R _{DS(ON)}	V _{GS} =10V, I _D =500mA	-	1.2	5	
		V _{GS} =4.5V, I _D =75mA	-	1.8	5.3	
Drain-Source ON Voltage	V _{DS(ON)}	V _{GS} =10V, I _D =500mA	-	0.6	2.5	V
		V _{GS} =4.5V, I _D =75mA	-	0.14	0.4	
On State Drain Current	$I_{D(ON)}$	V _{GS} =4.5V, V _{DS} =10V	75	600	-	mA
Forward Transconductance	g_{FS}	V _{DS} =10V, I _D =200mA	100	320	-	mS
Drain-Source Diode Forward Voltage	V_{SD}	V _{GS} =0V, I _S =200mA	-	0.76	1.15	V

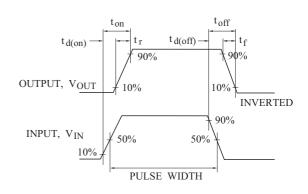
Note 1) Pulse Test: Pulse Width 300 \mu s, Duty Cycle 2.0%

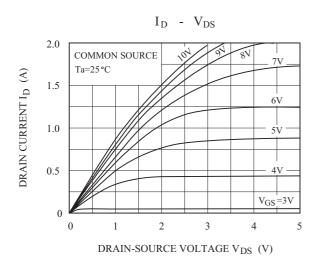
DYNAMIC CHARACTERISTICS

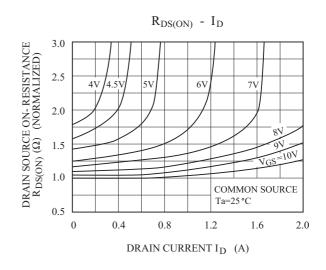
CHARAC	TERISTIC	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Input Capacitance		C _{iss}		-	20	50	
Reverse Transfer Ca	pacitance	C _{rss}	V_{DS} =25V, V_{GS} =0V, f=1MHz	-	4	5	pF
Output Capacitance C _{oss}		C _{oss}		-	11	25	
Switching Time	Turn-On Time	t _{on}	V _{DD} =15V, R _L =25 , I _D =200mA,	-	-	10	nS
	Turn-Off Time	t _{off}	$V_{GS}=10V, R_{GEN}=25$	-	-	10	

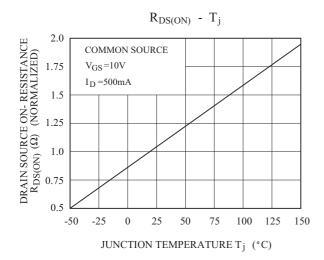
SWITCHING TIME TEST CIRCUIT

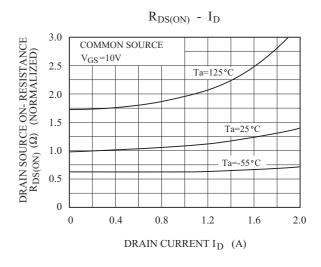


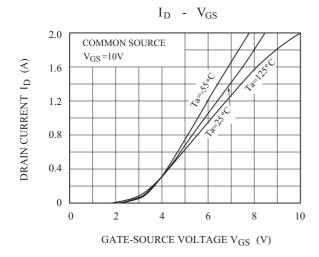


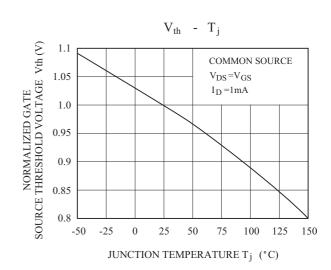


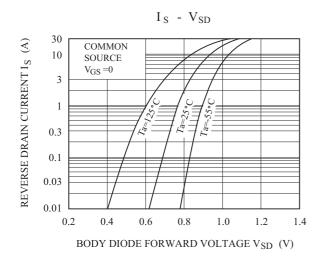


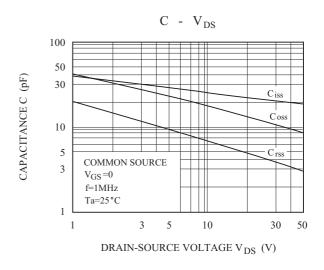


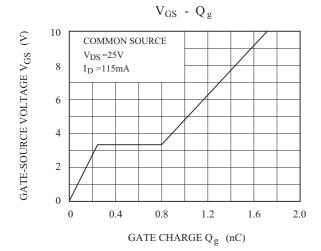


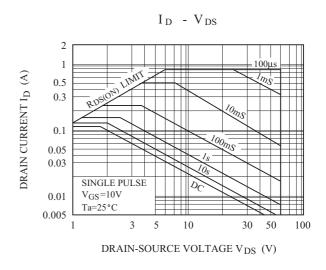


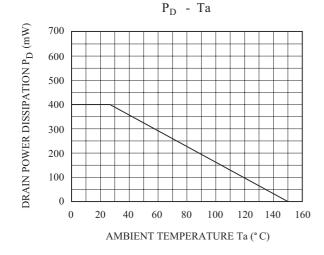












Revision No: 3